

## 25Ptlr200B-H or 25Ptlr200A-H

The 25Ptlr200B-H is the updated version of RMN's high frequency probe, with prolonged mechanical wear. It is typically used for non-contact and tapping mode AFM measurements. These probes are ideal for THz-SNOM, SNOM and high Frequency applications.

- Tip shank length: 80  $\mu\text{m}$  ( $\pm 25\%$ )
- Cantilever length: 200  $\mu\text{m}$  ( $\pm 15\%$ )
- Cantilever width: 50  $\mu\text{m}$  ( $\pm 15\%$ )
- Spring constant: 290 N/m ( $\pm 40\%$ )
- Frequency: 105 kHz ( $\pm 30\%$ )
- Standard tip radii below 20 nm for \$112 each
- Tip radii below 10 nm on request for \$134 each 25Ptlr200B-H10
- Non - standard probe tips and cantilevers upon request